

Methods, IMC, Mülhaupt

<h1>Multimode Atomic Force Microscope</h1> <p><i>AFM, two identical microscopes</i></p>	<p>Model: <i>Veeco DI Nanoscope 3</i> Unit and Room: <i>FMF, 1.UG,-01 006</i> Responsible: <i>Dr. Yi Thomann</i> Further information: <i>http://www.fmf.uni-freiburg.de/service/dienstleistungen/mikroskopie/index_html/</i></p>
<p>Short Description:</p> <p>Atomic Force Microscope with various imaging modes</p> <p>Available Experiments/Techniques:</p> <p>The multimode AFM allows the morphological and mechanical characterization of small samples with several imaging modes:</p> <ul style="list-style-type: none">- tapping mode- contact mode- phase, amplitude, height mode imaging-lateral force and torsion measurements- nanoindentationetc. <p>resolution < 1nm</p>	<p>Picture of the Equipment</p> 
<p>Special Equipment:</p> <p>Sample preparation equipment</p>	
<p>Measurements on the equipment are currently done by:</p>	<p><input type="checkbox"/> Students <input type="checkbox"/> Students after Introduction <input checked="" type="checkbox"/> Students after extensive training <input checked="" type="checkbox"/> Trained scientific service personal</p>
<p>Recent Publications, where this instrument was important (optional): Give citation</p>	<p>Macromolecules 2009, 42(15), 5684-5699 Langmuir (2007), 23(21), 10746-10755.</p>
<p>Typical problems that may be solved with this instrument:</p>	<p><i>The microscope allows the characterization of surfaces of nearly every material, and the investigation of bulk morphologies on microtomed samples. Topography and material properties can be imaged.</i></p>